

AI/ML for Particle Accelerator, X-Ray Beamlines and Electron Microscopy

Tuesday, 2 November 2021

Session IV: Imaging and Data Processing (13:30 - 15:45)

-Conveners: Charudatta Phatak

time	[id] title	presenter
13:30	[18] Using automated image analysis to understand nanoparticle coarsening, ripening and evaporation at the nanoscale	STACH, Eric
13:55	[19] Phase retrieval with deep learning network and automatic differentiation	ZHOU, Tao
14:20	[20] Overview of AI/ML@APS beamlines	CHERUKARA, Mathew
14:45	[21] Accelerated Data Analysis Workflows for Ptychography using Remote Leadership Computing Resources	BICER, Tekin
15:10	[22] Open / Speaker Panel Discussion	